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EXAMINER
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ART UNIT	PAPER NUMBER
2123	12

DATE MAILED: 09/08/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)	
	09/373,014	TSENG ET AL.	
	Examiner	Art Unit	
	Kandasamy Thangavelu	2123	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on *10 June 2003* .

2a)☐ This action is **FINAL**. 2b)☒ This action is non-final.

3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☒ Claim(s) *1-22* is/are pending in the application.

4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5)☐ Claim(s) _____ is/are allowed.

6)☒ Claim(s) *1-22* is/are rejected.

7)☐ Claim(s) _____ is/are objected to.

8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.

10)☒ The drawing(s) filed on *11 August 1999* is/are: a)☐ accepted or b)☒ objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

11)☐ The proposed drawing correction filed on _____ is: a)☐ approved b)☐ disapproved by the Examiner.

If approved, corrected drawings are required in reply to this Office action.

12)☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. §§ 119 and 120

13)☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a)☐ All b)☐ Some * c)☐ None of:

1.☐ Certified copies of the priority documents have been received.

2.☐ Certified copies of the priority documents have been received in Application No. _____ .

3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

14)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).

a) ☐ The translation of the foreign language provisional application has been received.

15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

Attachment(s)

1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☐ Information Disclosure Statement(s) (PTO-1449) Paper No(s) _____ .
4) ☐ Interview Summary (PTO-413) Paper No(s). _____ .
5) ☐ Notice of Informal Patent Application (PTO-152)
6) ☐ Other: .

DETAILED ACTION

Introduction

1. This communication is in response to the Applicants' Amendment dated June 10, 2003. Claims 1-7, 9 and 11-16 were amended. Claims 1-122 of the application are pending in the application. This office action is made non-final, in response to the Request for Continued Examination.

Response to Amendments

2. Applicant's arguments filed on June 10, 2003 have been fully considered. Claim rejections under 35 U.S.C. 112 first and second paragraphs are withdrawn in response to the applicant's amendments to the claims. New claim rejections under 35 USC 103(a) have been included in response to the amendments to the claims.

Drawings

3. The draft person has objected to the drawings; see a copy of Form PTO-948 sent with paper No. 5 for an explanation.

Claim Rejections - 35 USC § 103

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains.

5. The factual inquiries set forth in Graham v. John Deere Co., 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1. Determining the scope and contents of the prior art.
2. Ascertaining the differences between the prior art and the claims at issue.
3. Resolving the level of ordinary skill in the pertinent art.
4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

6. Claims 1, 2, 21, 3, 4, 7-13, 16-18 and 22 are rejected under 35 U.S.C. 103(a) as being unpatentable over **Takahashi et al. (TA)** (U.S. Patent 6,061,283) in view of **Lin (LI)** (U.S. Patent 6,421,251), and further in view of **Parulkar et al. (PA)** (U.S. Patent 6,363,509).

6.1 **TA** teaches semiconductor integrated circuit evaluation system. Specifically, as per Claim 1, **TA** teaches a method of creating a record of a debug session for a software modeled design on demand (CL4, L1-6; Fig 2A). **TA** does not expressly teach a method of creating a record of a debug session for a hardware modeled design on demand. **LI** teaches a method of creating a record of a debug session for a hardware modeled design on demand (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-

39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included the method of creating a record of a debug session for a hardware modeled design on demand, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach selecting a simulation session range. **LI** teaches selecting a simulation session range (CL13, L60-64), as the selected session range affects the simulation speed since the system must spend time and resources to record the output data to the memory (CL21, L9-15). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included selecting a simulation session range, as the selected session range would affect the simulation speed since the system must spend time and resources to record the output data to the memory.

TA does not expressly teach selecting a simulation target range wherein the simulation target range is within the simulation session_range. **LI** teaches selecting a simulation target range wherein the simulation target range is within the simulation session_range (CL13, L64 to CL14, L3), as the user can then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components (CL42, L46-49). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included selecting a simulation target range wherein the simulation target range is within the simulation

session_range, as the user could then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components.

TA teaches generating a Value change dump (VCD) file by dumping state information from the software modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach generating a Value change dump (VCD) file by dumping state information from the hardware modeled design. **LI** teaches generating a Value change dump (VCD) file by dumping state information from the hardware modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included generating a Value change dump (VCD) file by dumping state information from the hardware modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach generating a Value change dump (VCD) file by dumping state information for the selected simulation target range. **PA** teaches generating a Value change dump (VCD) file by dumping state information for the selected simulation target range (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the

functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** and **LI** with the method of **PA** that included generating a Value change dump (VCD) file by dumping state information for the selected simulation target range, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor.

Per claim 2: **TA** teaches accessing the VCD file directly from the beginning of the simulation target range to debug the modeled design (CL2, L56-61; CL5, L36-46).

TA teaches recording primary inputs to the software modeled design for evaluation (CL2, L54-60; CL1, L39-43). **TA** does not expressly teach recording primary inputs to the hardware modeled design for evaluation. **LI** teaches recording primary inputs to the hardware modeled design for evaluation (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included recording primary inputs to the hardware modeled design for evaluation, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA teaches recording state information from the software modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly recording state information from the hardware modeled design. **LI** teaches recording state information from the hardware modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included recording state information from the hardware modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach recording state information at the beginning of the simulation session range. **PA** teaches recording state information at the beginning of the simulation session range (CL10, L38-40), because as per **LI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **PA** that included recording state information at the beginning of the simulation session range, because the user could select a particular point at which the simulation is desired; then the user could select the start of session range which was recorded and simulate forward in

time until the simulation reached the desired point so the post simulation analysis point was reached fast.

Per Claim 21: **TA** does not expressly teach that the simulation session range begins at a simulation time t0 and ends at a simulation time t3. **LI** teaches that the simulation session range begins at a simulation time t0 and ends at a simulation time t3 (CL13, L60-64), as the selected session range affects the simulation speed since the system must spend time and resources to record the output data to the memory (CL21, L9-15). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included simulation session range beginning at a simulation time t0 and ending at a simulation time t3, as the selected session range would affect the simulation speed since the system must spend time and resources to record the output data to the memory.

TA does not expressly teach that the simulation target range begins at a simulation time t1 and ends at a simulation time t2, wherein the simulation time t1 is greater than or equal to simulation time t0 and simulation time t2 is less than or equal to simulation time t3. **LI** teaches that the simulation target range begins at a simulation time t1 and ends at a simulation time t2, wherein the simulation time t1 is greater than or equal to simulation time t0 and simulation time t2 is less than or equal to simulation time t3 (CL13, L64 to CL14, L3), as the user can then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components (CL42, L46-49). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included the simulation target range

beginning at a simulation time t1 and ending at a simulation time t2, wherein the simulation time t1 was greater than or equal to simulation time t0 and simulation time t2 was less than or equal to simulation time t3, as the user could then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components.

Per Claim 3: **TA** teaches evaluating in the modeled design from simulation time t0 to simulation time t2 (CL3, L39 to CL4, L26; CL1, L27-29; CL1, L34-35; CL3, L4-8; CL5, L34-37).

TA teaches recording primary inputs to the software modeled design for evaluation (CL2, L54-60; CL1, L39-43). **TA** does not expressly teach recording primary inputs to the hardware modeled design for evaluation. **LI** teaches recording primary inputs to the hardware modeled design for evaluation (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included recording primary inputs to the hardware modeled design for evaluation, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA teaches recording state information from the software modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly

recording state information from the hardware modeled design. **LI** teaches recording state information from the hardware modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included recording state information from the hardware modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach recording state information for a portion of the simulation session range. **PA** teaches recording state information for a portion of the simulation session range (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** and **LI** with the method of **PA** that included recording state information for a portion of the simulation session range, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 4: **TA** teaches the step of generating the VCD file further comprises generating evaluated results from the modeled design based on the recorded primary inputs and recorded state information (CL4, L21-26; CL1, L27-29; CL1, L34-35; CL3, L4-8; CL5, L34-37; CL5, L59-63).

TA teaches saving the evaluated results into the VCD file (CL4, L1-26; CL6, L21-36). **TA** does not expressly teach saving the evaluated results of the simulation target range into the VCD file. **PA** teaches saving the evaluated results of the simulation target range into the VCD file (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **PA** that included saving the evaluated results of the simulation target range into the VCD file, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 7: **TA** teaches recording primary inputs (CL2, L54-60; CL1, L39-43).

Per Claim 8: **TA** teaches recording state information of the modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach saving state information of the modeled design at simulation time t0 in a first file and

saving state information of the modeled design at simulation time t3 in a second file. **PA** teaches saving state information of the modeled design at simulation time t0 in a first file and saving state information of the modeled design at simulation time t3 in a second file (CL10, L38-48), because as per **LI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **PA** that included saving state information of the modeled design at simulation time t0 in a first file and saving state information of the modeled design at simulation time t3 in a second file, because the user could select a particular point at which the simulation is desired; then the user could select the start of session range which was recorded and simulate forward in time until the simulation reached the desired point so the post simulation analysis point was reached fast.

6.2 As per Claim 9, **TA** teaches an electronic design automation system for verifying a user design (Fig 2A); comprising:

a computing system including a central processing unit and memory for modeling the user design in software (Fig. 2A; CL4, L67 to CL5, L46; CL1, L27-29); and

an internal bus system coupled to the computing system (Fig 2A).

TA teaches hardware logic coupled to the internal bus system and for modeling at least a portion of the user design in hardware (Fig 2A, Item 22; CL3, L55-65). **TA** does not expressly teach reconfigurable hardware logic coupled to the internal bus system and for modeling at least

a portion of the user design in hardware. **LI** teaches reconfigurable hardware logic coupled to the internal bus system and for modeling at least a portion of the user design in hardware (CL18, L40-43), as the reconfigurable hardware can be programmably configured to model the hardware portion of the user's electronic system design (CL18, L40-43). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included reconfigurable hardware logic coupled to the internal bus system and for modeling at least a portion of the user design in hardware, as the reconfigurable hardware could be programmably configured to model the hardware portion of the user's electronic system design.

TA does not expressly teach control logic coupled to the internal bus system for controlling the delivery of data between the reconfigurable hardware logic and the computing system. **LI** teaches control logic coupled to the internal bus system for controlling the delivery of data between the reconfigurable hardware logic and the computing system (CL12, L51-61), as the that allows the entire circuit design to be modeled in software and the evaluation components to be modeled in hardware (CL12, L53-56), so the system can simulate the circuit in software for a time period and then accelerate the simulation in hardware (CL13, L10-11). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included control logic coupled to the internal bus system for controlling the delivery of data between the reconfigurable hardware logic and the computing system, as the that would allow the entire circuit design to be modeled in software and the evaluation components to be modeled in hardware, so the system could simulate the circuit in software for a time period and then accelerate the simulation in hardware.

TA teaches VCD on-demand logic for recording a selected simulation session (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach VCD on-demand logic for recording at least a portion of a selected simulation session range. **PA** teaches VCD on-demand logic for recording at least a portion of a selected simulation session range (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **PA** that included VCD on-demand logic for recording at least a portion of a selected simulation session range, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

TA teaches dumping state information from the software model into a VCD file (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach dumping state information from the hardware model into a VCD file. **LI** teaches dumping state information from the hardware model into a VCD file (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that

included dumping state information from the hardware model into a VCD file, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach dumping state information for a selected simulation target range, where the simulation target range is within the simulation session range. **PA** teaches dumping state information for a selected simulation target range, where the simulation target range is within the simulation session range (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** and **LI** with the method of **PA** that included dumping state information for a selected simulation target range, where the simulation target range is within the simulation session range, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 10: **TA** teaches access logic for accessing the VCD file directly from simulation time tl to debug the user design (CL2, L56-61; CL5, L36-46).

TA does not expressly teach first range selection logic for selecting a simulation session range which begins at a simulation time t0 and ends at a simulation time t3. **LI** teaches first

range selection logic for selecting a simulation session range which begins at a simulation time t0 and ends at a simulation time t3 (CL13, L60-64), as the selected session range affects the simulation speed since the system must spend time and resources to record the output data to the memory (CL21, L9-15). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included first range selection logic for selecting a simulation session range which begins at a simulation time t0 and ends at a simulation time t3, as the selected session range would affect the simulation speed since the system must spend time and resources to record the output data to the memory.

TA does not expressly teach second range selection logic for selecting a simulation target range which begins at a simulation time t1 and ends at a simulation time t2, wherein the simulation time t1 is greater than or equal to simulation time t0 and simulation time t2 is less than or equal to simulation time t3. **LI** teaches second range selection logic for selecting a simulation target range which begins at a simulation time t1 and ends at a simulation time t2, wherein the simulation time t1 is greater than or equal to simulation time t0 and simulation time t2 is less than or equal to simulation time t3 (CL13, L64 to CL14, L3), as the user can then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components (CL42, L46-49). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included second range selection logic for selecting a simulation target range which began at a simulation time t1 and ended at a simulation time t2, wherein the simulation time t1 is greater than or equal to simulation time t0 and simulation time t2 is less than or equal to simulation time t3, as the user could then perform

analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components.

TA teaches dump logic for generating a VCD file of the software-modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach dump logic for generating a VCD file of the hardware-modeled design. **LI** teaches dump logic for generating a VCD file of the hardware-modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included dump logic for generating a VCD file of the hardware-modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach dump logic for generating a VCD file for the selected simulation target range. **PA** teaches dump logic for generating a VCD file for the selected simulation target range (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** and **LI** with the system of **PA** that included dump logic for generating a VCD file

for the selected simulation target range, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 11: **TA** teaches that the VCD on-demand logic further comprises test bench process for providing primary inputs to the hardware-modeled design for evaluation (CL1, L32-33); and

recording logic in the computing system for recording data associated with at least one parameter in the simulation session rang (CL6, L9-13; CL6, L21-25).

Per Claim 12: **TA** teaches that the VCD on-demand logic further comprises process logic in the computing system for loading the recorded data associated with at least one parameter (CL6, L21-27).

TA teaches evaluation logic in the hardware logic for evaluating in the hardware-modeled design the primary inputs from simulation time t0 to simulation time t2 (Fig 2A, Item 22; CL3, L55-65; CL6, L30-36). **TA** does not expressly teach evaluation logic in the reconfigurable hardware logic for evaluating in the hardware-modeled design the primary inputs from simulation time t0 to simulation time t2. **LI** teaches evaluation logic in the reconfigurable hardware logic for evaluating in the hardware-modeled design the primary inputs from simulation time t0 to simulation time t2 (CL18, L40-43), as the reconfigurable hardware can be programmably configured to model the hardware portion of the user's electronic system design

(CL18, L40-43). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included evaluation logic in the reconfigurable hardware logic for evaluating in the hardware-modeled design the primary inputs from simulation time t0 to simulation time t2, as the reconfigurable hardware could be programmably configured to model the hardware portion of the user's electronic system design.

Per Claim 13: **TA** teaches the dump logic dumps the evaluated results from the software-modeled design based on the primary inputs during the simulation into the VCD file (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach the dump logic dumps the evaluated results from the hardware-modeled design based on the primary inputs during the simulation into the VCD file. **LI** teaches the dump logic dumps the evaluated results from the hardware-modeled design based on the primary inputs during the simulation into the VCD file (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included the dump logic dumping the evaluated results from the hardware-modeled design based on the primary inputs during the simulation into the VCD file, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach the dump logic dumps the evaluated results based on the primary inputs during the simulation target range into the VCD file. **PA** teaches the dump logic dumps the evaluated results based on the primary inputs during the simulation target range into the VCD file (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** and **LI** with the system of **PA** that included the dump logic dumping the evaluated results based on the primary inputs during the simulation target range into the VCD file, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 16: **TA** teaches write logic for writing the primary inputs (CL2, L54-60; CL1, L39-43).

TA teaches write logic for writing state information from the software model (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly write logic for writing state information from the hardware model. **LI** teaches write logic for writing state information from the hardware model (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit

design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included write logic for writing state information from the hardware model, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach write logic for writing state information at simulation time t0. **PA** teaches write logic for writing state information at simulation time t0 (CL10, L38-40), because as per **LI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **PA** that included write logic for writing state information at simulation time t0, because the user could select a particular point at which the simulation was desired; then the user could select the start of session range which was recorded and simulate forward in time until the simulation reached the desired point so the post simulation analysis point was reached fast.

Per Claim 17: **TA** teaches state save logic for saving state information of the software modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach state save logic for saving state information of the hardware-modeled design. **LI** teaches state save logic for saving state information of the hardware-modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled

design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included state save logic for saving state information of the hardware-modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach state save logic for saving state information at simulation time t0 in a first file and saving state information at simulation time t3 in a second file. **PA** teaches state save logic for saving state information at simulation time t0 in a first file and saving state information at simulation time t3 in a second file (CL10, L38-48), because as per **TI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **PA** that included state save logic for saving state information at simulation time t0 in a first file and saving state information at simulation time t3 in a second file, because the user could select a particular point at which the simulation is desired; then the user could select the start of session range which was recorded and simulate forward in time until the simulation reached the desired point so the post simulation analysis point was reached fast.

6.3 As per Claim 18, **TA** teaches a VCD on-demand system for providing evaluated information for selected simulation times, the evaluation occurring in a software model (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach a VCD on-demand system for providing evaluated information for selected simulation times, the evaluation occurring in a hardware model. **LI** teaches a VCD on-demand system for providing evaluated information for selected simulation times, the evaluation occurring in a hardware model (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included a VCD on-demand system for providing evaluated information for selected simulation times, the evaluation occurring in a hardware model, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach a VCD on-demand system for providing evaluated information for a selected simulation target range of simulation times. **PA** teaches a VCD on-demand system for providing evaluated information for a selected simulation target range of simulation times (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10, L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been

obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** and **LI** with the system of **PA** that included a VCD on-demand system for providing evaluated information for a selected simulation target range of simulation times, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

TA does not expressly teach first logic for selecting a simulation session range. **LI** teaches first logic for selecting a simulation session range (CL13, L60-64), as the selected session range affects the simulation speed since the system must spend time and resources to record the output data to the memory (CL21, L9-15). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included first logic for selecting a simulation session range, as the selected session range would affect the simulation speed since the system must spend time and resources to record the output data to the memory.

TA does not expressly teach second logic selecting a simulation target range, wherein the simulation target range is within the simulation session range. **LI** teaches second logic selecting a simulation target range, wherein the simulation target range is within the simulation session range (CL13, L64 to CL14, L3), as the user can then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components (CL42, L46-49). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included second logic selecting a simulation target range, wherein the

simulation target range is within the simulation session range, as the user could then perform analysis after simulation, by running the software simulation with input logs to the hardware model to compute the value change dump of all hardware components.

TA teaches generation logic for generating a VCD file of the evaluated information by dumping state information from the software model (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly teach generation logic for generating a VCD file of the evaluated information by dumping state information from the hardware model. **LI** teaches generation logic for generating a VCD file of the evaluated information by dumping state information from the hardware model (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included generation logic for generating a VCD file of the evaluated information by dumping state information from the hardware model, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA and **LI** do not expressly teach generation logic for generating a VCD file of the evaluated information for the selected simulation target range by dumping state information. **PA** teaches generation logic for generating a VCD file of the evaluated information for the selected simulation target range by dumping state information (CL10, L21-38), as the simulation results of the simulation model can be used on a physical implementation of the model to test it (CL10,

L54-56) and as per **TA**, the IC evaluation system can perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device (CL5, L58-62). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** and **LI** with the system of **PA** that included generation logic for generating a VCD file of the evaluated information for the selected simulation target range by dumping state information, as the simulation results of the simulation model could be used on a physical implementation of the model to test it and as per **TA**, the IC evaluation system could perform evaluation of the test patterns for testing the semiconductor device and the functions of the semiconductor device.

Per Claim 22: This is a system claim having the same limitations as Claim 21. So Claim 22 is rejected based on the same reasoning as Claim 21, supra.

7. Claims 5, 6, 14, 15, 19 and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over **Takahashi et al. (TA)** (U.S. Patent 6,061,283) in view of **Lin (LI)** (U.S. Patent 6,421,251) and **Parulkar et al. (PA)** (U.S. Patent 6,363,509), and further in view of **Matsumura et al. (MA)** (U.S. Patent 6,370,675).

7.1 As per Claim 5, **TA, LI** and **PA** teach the method of Claim 1. **TA, LI** and **PA** do not expressly teach compressing the primary inputs recording the compressed primary inputs. **MA** teaches compressing the primary inputs recording the compressed primary inputs (Abstract, L12-15; CL5, L55 to CL6, L10), as the test pattern data after compression is stored in the memory

(CL10, L54-56) and the memory required will be reduced by compression. It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA, LI** and **PA** with the method of **MPA** that included compressing the primary inputs recording the compressed primary inputs, as the test pattern data after compression would be stored in the memory and the memory required would be reduced by compression.

TA teaches recording state information from the software modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly recording state information from the hardware modeled design. **LI** teaches recording state information from the hardware modeled design (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the method of **TA** with the method of **LI** that included recording state information from the hardware modeled design, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach recording state information at the start of the simulation session range. **PA** teaches recording state information at the start of the simulation session range (CL10, L38-40), because as per **LI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the

art at the time of Applicants' invention to combine the method of **TA** with the method of **PA** that included recording state information at the start of the simulation session range, because the user could select a particular point at which the simulation was desired; then the user could select the start of session range which was recorded and simulate forward in time until the simulation reached the desired point so the post simulation analysis point was reached fast.

Per Claim 6: **TA** teaches decompressing the compressed primary inputs (CL2, L29-31); and

providing the decompressed primary inputs to the modeled design for evaluation (CL1, L32-33; CL2, L31-33; Fig. 1, Blk 17, 10 and 11).

7.2 As per Claim 14, **TA, LI** and **PA** teach the system of Claim 13. **TA, LI** and **PA** do not expressly teach compression logic for compressing the primary inputs and write logic for writing the compressed primary inputs. **MA** teaches compression logic for compressing the primary inputs and write logic for writing the compressed primary inputs (Abstract, L12-15; CL5, L55 to CL6, L10), as the test pattern data after compression is stored in the memory (CL10, L54-56) and the memory required will be reduced by compression. It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA, LI** and **PA** with the system of **MA** that included compression logic for compressing the primary inputs and write logic for writing the compressed primary inputs, as the test pattern data after compression would be stored in the memory and the memory required would be reduced by compression.

TA teaches write logic for writing state information from the software model (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25). **TA** does not expressly write logic for writing state information from the hardware model. **LI** teaches write logic for writing state information from the hardware model (CL3, L56-62; CL5, L34-40; CL18, L40-43), as the hardware modeled design provides high speed (CL3, L38-39) and the user can accelerate the test/debug process by running the simulation through the hardware model of the circuit design (CL20, L24-26). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **LI** that included write logic for writing state information from the hardware model, as the hardware modeled design would provide high speed and the user could accelerate the test/debug process by running the simulation through the hardware model of the circuit design.

TA does not expressly teach write logic for writing state information at simulation time t0. **PA** teaches write logic for writing state information at simulation time t0 (CL10, L38-40), because as per **LI** the user can select a particular point at which the simulation is desired; then the user can select the start of session range which is recorded and simulate forward in time until the simulation reaches the desired point so the post simulation analysis point is reached fast (CL42, L23-45). It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA** with the system of **PA** that included write logic for writing state information at simulation time t0, because the user could select a particular point at which the simulation was desired; then the user could select the start of session range which was recorded and simulate forward in time until the simulation reached the desired point so the post simulation analysis point was reached fast.

Per Claim 15: **TA** teaches the process logic further comprises decompression logic for decompressing the compressed primary inputs (CL2, L29-31); and

data transfer logic for delivering the decompressed primary inputs to the hardware-modeled design for evaluation (CL1, L32-33; CL2, L31-33; Fig. 1, Blk17, 10 and 11).

7.3 As per Claim 19, **TA, LI** and **PA** teach the system of Claim 18. **TA** teaches access logic for accessing the VCD file directly from the beginning of the simulation target range to debug the modeled design (CL2, L56-61; CL5, L36-46); and

decompression logic for decompressing the compressed primary input data (CL2, L29-31) and delivering the decompressed primary input data into the modeled design for evaluation (CL1, L32-33; CL2, L31-33; Fig. 1, Blk17, 10 and 11).

TA, LI and **PA** do not expressly teach compression logic for receiving and compressing primary input data for the duration of the simulation session range. **MA** teaches compression logic for receiving and compressing primary input data for the duration of the simulation session range (Abstract, L12-15; CL5, L55 to CL6, L10), as the test pattern data after compression is stored in the memory (CL10, L54-56) and the memory required will be reduced by compression. It would have been obvious to one of ordinary skill in the art at the time of Applicants' invention to combine the system of **TA, LI** and **PA** with the system of **MA** that included compression logic for receiving and compressing primary input data for the duration of the simulation session range, as the test pattern data after compression would be stored in the memory and the memory required would be reduced by compression.

Per Claim 20: **TA** teaches dump logic for dumping evaluated information to the VCD file, the evaluated information generated by the evaluation of the decompressed primary inputs by the modeled design (CL2, L56-61; CL1, L27-29; CL4, L5-6; CL1, L62-65; CL5, L40-44; CL6, L21-25).

Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dr. Kandasamy Thangavelu whose telephone number is 703-305-0043. The examiner can normally be reached on Monday through Friday from 8:00 AM to 5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kevin Teska, can be reached on (703) 305-9704. The fax phone number for the organization where this application or proceeding is assigned is 703-746-73210.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-305-9600.

K. Thangavelu
Art Unit 2123
September 2, 2003

KEVIN J. TESKA
SUPERVISORY
PATENT EXAMINER